

UNITED STATES PATENT AND TRADEMARK OFFICE  
**CERTIFICATE OF CORRECTION**

PATENT NO. : 6,948,149 B2  
DATED : September 20, 2005  
INVENTOR(S) : Goodwin

Page 1 of 3

It is certified that error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

Column 9, line 28 through Column 10, line 57.  
Claims 9-18 should read:

9. The method according to claim 7, wherein forming the subsets comprises choosing three or more exposure fields having positions on the test wafer, which are arranged substantially concentric around the center of the test wafer.

10. The method according to claim 7, further comprising defining a concentric area, preferably a ring or an inner circle on the test wafer; and selecting the at least two subsets of exposure fields having positions on the test wafer, which are arranged within the concentric area.

11. The method according to claim 10, wherein an outer ring and an inner circle are defined as concentric areas on the test wafer, and one subset is formed each from exposure fields positioned within the inner circle or from exposure fields formed within said outer ring, and the steps of obtaining shifts, determining the second sets of error values, comparing the first and second sets of error values and selecting a subset in dependence of the comparison results are performed for each of the subsets corresponding to the exposure fields formed within the outer ring and the inner circle, separately.

12. The method according to claim 11, further comprising: combining the selected subsets, which have been selected separately from within the outer ring or from within the inner circle, into one selected subset of exposure fields.

13. The method according to claim 7, wherein the first and/or the second set of correctable or non-correctable error values are each one or a combination of:  
a mean value,  
modeled errors,  
residuals,  
3 sigma variation or  
a total range of the measured shifts.

14. The method according to claim 8, wherein the first and/or the second set of correctable or non-correctable error values are each one or a combination of:  
a mean value,  
modeled errors,  
residuals,  
3 sigma variation or  
a total range of the measured shifts.

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Column 9, line 28 through Column 10, line 57, (cont'd).

15. The method according to claim 9, wherein the first and/or the second set of correctable or non-correctable error values are each one or a combination of:

a mean value,  
modeled errors,  
residuals,  
3 sigma variation or  
a total range of the measured shifts.

16. The method according to claim 10, wherein the first and/or the second set of correctable or non-correctable error values are each one or a combination of:

a mean value,  
modeled errors,  
residuals,  
3 sigma variation or  
a total range of the measured shifts.

17. The method according to claim 11, wherein the first and/or the second set of correctable or non-correctable error values are each one or a combination of:

a mean value,  
modeled errors,  
residuals,  
3 sigma variation or  
a total range of the measured shifts.

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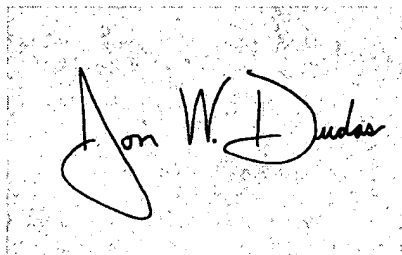
Column 9, line 28 to Column 10, line 57, (cont'd).

18. The method according to claim 12, wherein the first and/or the second set of correctable or non-correctable error values are each one or a combination of:

a mean value,  
modeled errors,  
residuals,  
3 sigma variation or  
a total range of the measured shifts.

Signed and Sealed this

Twentieth Day of December, 2005

A handwritten signature in black ink, reading "Jon W. Dudas", is written over a rectangular, textured background that appears to be a stamp or a piece of paper with a grainy texture.

JON W. DUDAS

*Director of the United States Patent and Trademark Office*